

PTO/SB/08A (07-06)

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**Substitute for form 1449/PTO**

## **INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 1

of 2

**Complete if Known**

Application Number	10/596,373
Filing Date	December 10, 2004
First Named Inventor	Aviram Tam
Art Unit	Unknown 4174
Examiner Name	Unknown Kenny Ceser
Attorney Docket Number	40006317-0097-002

**U. S. PATENT DOCUMENTS**

## FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)			

Examiner Signature	/Kenny Cesei/	Date Considered	04/16/2011
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Translation is attached.  
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<b>NON PATENT LITERATURE DOCUMENTS</b>				
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		T <sup>2</sup>
/K.C./		NELSON et al, "Comparison of Metrology Methods for Quantifying the Line Edge Roughness of Patterned Features", Journal of Vacuum Science and Technology B17(6), pp 2488-2498		
/K.C./		VANDEWEYER et al., "The Measurement of Contact Edge Roughness in 193nm Patterning", in Interface 2003, September 2003		

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